

Low Droop Rate/Accurate Sample-and-Hold Amplifiers

SMP-10/SMP-11

FEATURES

		•
SM	P-1	O

•	Low Droop Rate 5.0μV/ms	ì
•	Linearity Error	•
•	High Sample/Hold Current Ratio 2 x 10)

SMP-11

•	Low Droop Rate Over Temperature	2400µV/ms
	High Sample/Hold Current Ratio	1.7 x 10°

BOTH SMP-10 AND SMP-11 Fast Acquisition Time, 10V Step to 0.1% 3.5µs

•	High Slew Rate	10V/µs
•	Low Aperture Time	50ns
•	Trimmed for Minimum Zero-Scale Error	0.45mV
•	m tot I Assessable Makin	0645

Feedthrough Attenuation Ratio 96dB Low Power Dissipation...... 160mW

DTD, TTL & CMOS Compatible Logic input NX-2420, HA-2425, SHM-IC-1, and AD583 Socket Compatible Available in Die Porton

ORDERING INFORMATION 4

TAG	+25°C	-	ACKAGE	
Vzs (mV)	DROOP RATE IN µV/ms	DROOP RATE IN 14-PIN DIP		OPERATING TEMPERATURE RANGE
1.5	20	SMP10AY	_	MIL
1.5	20	SMP10EY	-	COM
3.0	50	SMP10FY	-	COM
1.5	200	SMP11AY*	-	MIL
3.0	500	SMP11BY*	SMP11BRC/883	MIL
1.5	200	SMP11EY	-	COM
3.0	500	SMP11FY	-	COM
7.0	900	SMP11GY	-	COM
7.0	900	SMP11GS	-	XIND
7.0	900	SMP11GP		XIND

For devices processed in total compliance to MIL-STD-883, add /883 after part number. Consult factory for 883 data sheet.

GENERAL DESCRIPTION

The SMP-10/11 are precision sample-and-hold amplifiers that provide the high accuracy, the low droop rate and the fast acquisition time required in data acquisition and signal processing systems. Both devices are essentially noninverting unity gain circuits consisting of two very high input impedance buffer amplifiers connected together by a diode bridge switch.

HIGH ACCURACY AND LOW DROOP RATE

The high input impedance and the low droop rates of the SMP-10 and the SMP-11 are achieved by using bipolar Darlington circuits and an ion implant process that creates "super beta" transistors.

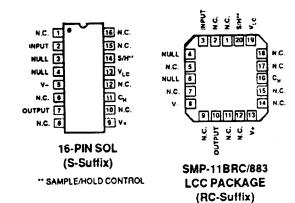
The output buffer's input stage converts to a super beta Darlington configuration during the hold mode, which results in a very

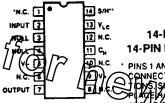
REV. C

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low droop rate with no penalty in acquisition time. The use of bipolar transistors achieves a low change in droop rate over the operating temperature range.

PIN CONNECTIONS

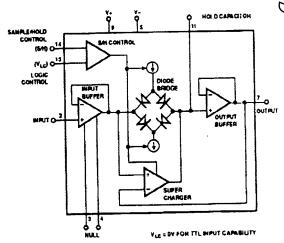




14-PIN DIP (Y-Suffix) 14-PIN EPOXY DIP (P-Suffix)

PINS 1 AND 8 ARE NOT INTERNALLY ONNECTED, IN UNITY GAIN APPLICA 10/AND SMP-11 CAN RE-M20 SHM-IC-1

FUNCTIONAL DIAGRAM



S/H	MODE
0	Sample
1	Hold

Manufactured under the following patents: 4,109,215 and 4,142,117.

One Technology Way, P.O. Box 9106, Norwood, MA 02062-9106, U.S.A. Fax: 617/326-8703 Twx: 710/394-6577 Tel: 617/329-4700 Cable: ANALOG NORWOODMASS Telex: 924491

Burn-in is available on commercial and industrial temperature range parts in CerDIP, plastic DIP, and TO-can packages.

GENERAL DESCRIPTION Continued

FAST ACQUISITION

A unique super charger provides up to 50mA of charging current to the hold capacitor, which results in smooth, fast charging with minimum noise. As the hold capacitor voltage nears its final value, the low current diode bridge controls the final settling time. This unique combination of linear functions in a monolithic circuit enables the system designer to achieve superior performance.

ABSOLUTE MAXIMUM RATINGS (N	
Supply Voltage (V+ minus V-)	36V
Derate Above 100°C	
Input Voltage Eq	
Logic and Logic Reference	
Voltage Eq	ual to Supply Voltage
Output Short-Circuit Duration	Indefinite
Hold Capacitor Short-Circuit Duration	
Storage Temperature Range	
Lead Temperature (Soldering, 60 sec)	300°C

Operating Temperature Ra	nge		
SMP-10AY		55°C	to +125°C
SMP-10EY, FY			
SMP-11AY, BY, BRC			
SMP-11EY, FY, GY			
SMP11GS, GP			
Junction Temperature (T _j)			
PACKAGE TYPE	⊖ _{IA} (Note 2)	e _{ic}	UNITS
14-Pin Hermetic DIP (Y)	108	16	*C/W
14-Pin Epoxy DIP (P)	83	39	*C/W
16-Pin SOL (S)	98	30	°C/W
20-Contact LCC (RC)	98	38	°C/W
NOTES:			

- 1. Absolute ratings apply to both DICE and packaged parts, unless otherwise
- Θ_M is specified for worst case mounting conditions, i.e., Θ_M is specified for device in socket for CerDIP and LCC packages.

ELECTRICAL CHARACTERISTICS at V_S = ±15V, C_H = 0.005µF, V_{LC} connected to ground, T_A = +25°C, unless otherwise noted.

T Reco			SMP-10A/E SMP-11A/E					SMP-10 SMP-11			SMP-11G				
PARAMETER	> ZYMADQI(Oc)ONDITYONS,	_	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	UNITS		
Zero-Scale Error (Hold Mode)	Vzs	V _{IN} = 0 V _{S/M} = 3.5V, (No.)/D	$\sqrt{7}^{45}$	1.5	-	0.60	3.0	-	1.5	7.0	πV		
Input Bias Current	l _B	V _{IN} = 0		~U [](0/30	(SS)		55	90	-	90	160	nA		
Leakage (Droop) Current	IDR	SMP-10 SMP-11		-	-1/6	> (G)	[](-	<u> </u>	0.25 /2.50	-	-	4.5	nA		
Droop Rate	dVCH/d≀	SMP-10 SMP-11		-	5 60	20 200	-) [] 5 70	[] 500		1/7 80/	<u></u>	μV/ms		
Input Resistance	R _{IN}	(Note 1)		2.0	3.0	-	1.4	2.5		<u> </u>	2.0		2) (4		
Voltage Gain	A _V	Sample Mode V _{IN} = ±10V, R _L = or V _{IN} = ±5V, R _L		0.99963	0.99983	-	0.99953	0,99978	-	0.99940	0.99975	-	> (2)		
Acquisition Time	I _{aq}	10V Step to With of Final Value (0, 10V Step to With	1%)	-	3.5 5.0	*	•	3.5 5.0	-	_	3.5	_	μs		
		of Final Value (0.	01%)								5.0		μς		
Aperture Time	lap				50	_		50	-	-	50	-	ns		
Hold Mode Settling Time	l _{Hm}	Settling to 1mV of Final Value.	SMP-10 SMP-11	-	7 1,5	-	-	7 1.5	-	- -	7 1.5	-	μ5		
Charge Transfer	Qt .	V _{IN} = 0 V _{S/H} = 3.5V		-	5	-	-	5	-	_	5		ρC		
Slew Rate	SR	V _{IN} = ±10V R _L = 2.5kΩ		-	10	-	-	10	_	-	10	-	V/µs		
Hold Capacitor Charging Current	СН	V _{IN} - V _{OUT} ≥±3V		30	50	-	20	50	-	-	50	-	mΑ		
Sample/Hold Current Ratio	Ich/loa		SMP-10 SMP-11	3x10 ⁸	2x10 ⁹ 1.7x10 ⁸	-	8x10 ⁷	8x10 ⁸ 1.5x10 ⁸	-	-	1.5x10 ⁸	-	mA/mA		
Feedthrough Attenuation Ratio	FA	Input = $20V_{p-p}$ 1k R _L = $5k\Omega$, (Note 1	Hz)	86	98	-	80	90	-	-	90	<u>-</u>	dB		
Full Power Bandwidth	Fp	±10V _{p-p} (Dissipation Limit	ed)	-	100	_	-	100		-	100	-	kHz		

ELECTRICAL CHARACTERISTICS at $V_S = \pm 15V$, $C_H = 0.005 \mu F$, V_{LC} connected to ground, $T_A = +25 \,^{\circ}$ C, unless otherwise noted.

OOM, MOO		· · · · · · · · · · · · · · · · · · ·		MP-10A MP-11A			SMP-10 MP-118		•	MP-110	;	
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
Input Voltage Range and/or Output Voltage Swing		R _L = 2.5kΩ	±11	±11.5		±10.5	±11.5	-	±10.5	±11.5	-	V
Output Resistance	Ro		<u> </u>	0.15		***	0.15		-	0.15		Ω
Power Supply Rejection Ratio	PSRR	Sample Mode V _S = ±9V to ±18V	82	92		77	92	-	72	92	-	₫B
Power Consumption (DC)	PD	Sample Mode V _{IN} = 0	-	160	180	-	170	210	-	180	240	mW

NOTES:

ELECTRICAL CHARACTERISTICS – SMP-10 ONLY at $V_S = \pm 15V$, $C_H = 0.005 \mu F$, $V_{LC} = 0V$, $T_A = +25 ^{\circ}C$, device fully warmed up, unless otherwise noted.

1 ~			S	MP-10/	VE	:			
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
HOM STEP (2)	∑ v [⊬] s	V _{IN} = 0	-1.0	+1.5	+4.0	-3.0	+1.5	+6.0	mV_
Linearity Error	> ONTO 12	V _{IN} = ±10V, R _L = 5kΩ	-	0.005	-	_	0.007		% of 10V
Output Noise	E _{N (AMS)}	Widelyand bloise 100Hz	-	40	-	-	50	-	µVямs

ELECTRICAL CHARACTERISTICS at V_S = ±15V, C_H = 0.005pP, V_{LC}connected to ground, 0°C ≤ T_A ≤ +70°C, unless otherwise noted.

			SMP-10E S SMP-11E S				SMP-10FU SMP-11F			SMP-1		
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	MIN	430		SALLAN TO
Zero-Scale Error	Vzs	V _{IN} = 0, V _{S/H} = 3.5V, (Note 1) -	0.75	2.0	_	1.0	4.0		2.7	10	
Input Bias Current	l _S	V _{IN} = 0V	-	50	90	-	80	140	_	120	250	-^^
Leakage (Droop) Current	IDR	SMP-10 SMP-11	-	0.05 0.5	0.25 1.8	-	0.080 0.6	0.65 2.8		- 0.7	- 5	An
Droop Rate	dV _{C+I} /dt	SMP-10 SMP11	- -	10 100	50 360	-	16 120	130 560	-	140	1000	μV/ms
Voltage Gain	Av	Sample Mode $V_{IN} = \pm 10V, R_L = 5k\Omega$ or $V_{IN} = \pm 5V, R_L = 2.5k\Omega$	0.99955	0.99976	-	0.99950	0.99972	-	0.99930	0.99970	-	v ⁄v
Power Supply Rejection Ratio	PSRR	Sample Mode V _S = ±9V to ±18V	80	90	-	75	80	-	70	90	-	dB
Logic Control Input Current	I _{LC}	V _{LC} ≈ 0V	-	-1	-2	_	-1	-3		-1	-4	ДА
Logic Input	Isnu	Sample Mode V _{S/H} = 0.6V	_	-5	-15	-	-5	-15	-	-5	-15	μА
Logic input	15/H	Hold Mode V _{S/H} = 5.0V	-	0.2	÷	-	0.2	-	-	0.2	-	n A
Differential Logic Threshold	V _{IH}		8.0	1.3	2.0	8.0	1.3	2.0	0.8	1.3	2.0	٧

NOTE:

^{1.} Guaranteed by design.

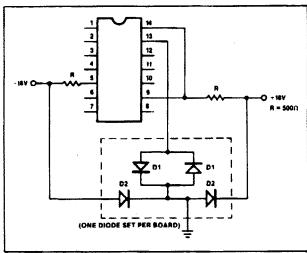
^{2.} Measured 500µs after hold command.

^{1.} Measured 500µs after hold command.

ELECTRICAL CHARACTERISTICS at $V_S = \pm 15V$, $C_H = 0.005 \mu F$, V_{LC} connected to ground, $-55 ^{\circ}C \le T_A \le + 125 ^{\circ}C$, unless otherwise noted.

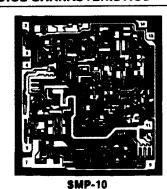
					SMP-10			SMP-1		
PARAMETER	SYMBOL	CONDITIONS		MIN	SMP-11	MAX	MIN	SMP-11 TYP	MAX	UNITS
Zero-Scale Error	Vzs	V _{IN} = 0, V _{S/H} = 3.5V	, (Note 1)	_	1.25	3.0		1.60	5.5	m∨
Input Bias Current	18	V _{IN} = 0V		-	90	180	_	160	280	nA
Leakage (Droop) Current	, DB	T _A = −55°C T _A = +125°C T _A = Full Range	SMP-10 SMP-11	_ 	0.050 12 12	0.50 20 20		0.080 16 16	1.22 25 25	nA
Droop Ratc	dV _{CH} /dt	T _A = −55°C T _A = ±125°C T _A = Full Range	SMP-10 SMP-11	_ _ _	10 2400 2400	100 4000 4000	· -	16 3200 3200	250 5000 5000	µV/ms
Voltage Gain	A _v	Sample Mode V _{IN} = ±10V, R _L = 5k or V _{IN} = ±5V, R _L = 7		0.99950	0.99972	_	0.99940	0.99968	_	V/V
Power Supply Rejection Ratio	PSRR	Sample Mode V _S = ±9V to ±18V		78	88	_	72	90		σВ
logiq Control Topus Current	ارد	V _{LC} = 0V			-1	-3		-1	5	<u> </u>
Logic Input		Sample Mode $V_{S/H} = 0.6V$ $H630 Mode$			-5	-15		~5 0.2	- 15 	μA nA
Differential Logic Threshold	V _{TH}		Nod	26	7 /2	2.0	0.6		2.0	٧
NOTES: 1. Measured 500µs after hold BURN-IN CIRCUIT	command.		·		15((7](0	<u>M</u>		7 [F	
BONN-IN CINCOIT									\mathcal{L}	
1 2 3	13 12 11									

BURN-IN CIRCUIT



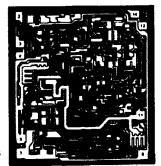
^{1.} Measured 500µs after hold command.

DICE CHARACTERISTICS



- 2. INPUT
- 3. NULL
- 4. NULL
- 5. NEGATIVE SUPPLY (SUBSTRATE)
- 7. OUTPUT
- POSITIVE SUPPLY
- 11. HOLD CAPACITOR (CH)
- LOGIC THRESHOLD CONTROL (VLC)
- SAMPLE/HOLD COMMAND

DIE SIZE 0.088 - 0.083 Inch, 7304 sq. mils (2.235 × 2.108 mm, 4.711 sq. mm)



NEGATIVE SUPPLY

2. INPUT

3. NULL

4. NULL

- (SUBSTRATE) OUTPUT
- 9. POSITIVE SUPPLY
- 11. HOLD CAPACITOR (CH)
- 13. LOGIC THRESHOLD
- CONTROL (VLC)
 SAMPLE/HOLD COMMAND

SMP-11

WAFER TEST LIMITS at $V_S = \pm 15V$, $C_H = 0.005 \mu F$, V_{LC} connected to ground, $T_A = 25^{\circ}C$, unless otherwise noted.

SMP-10G SMP-10N SMP-11G SMP-11N LIMIT LIMIT UNITS CONDITIONS SYMBOL V_{IN} = 0, V_{S/H} = 3.5V 1.5 3.0 mV MAX Vzs Hold Mode, : Note 2 60 90 na Max $V_{iN} = 0V$ Input Bias Current 0.25 0.10 nA MAX Leakage : Droop: Current IDR 2.5 20 50 SMP-10 μV/ms MAX Droop Rate dV_{CH}/dt 500 SMP-11 Sample Mode V/V MIN $V_{IN} = \pm 10V$ Voltage Gain or V_{IN} = ±5V Hold Capacitor 30 VIN " VOUT 2 # 3V CH **Charging Current** Input Voltage Range and/or ± 10.5 1.11 $R_L = 2.5k\Omega$ **Output Voltage Swing** Sample Mode **Power Supply** dB MIN 77 82 **PSRR** $V_S = \pm 9V \text{ to } \pm 18V$ Rejection Ratio 210 mW MAX Sample Mode V_{IN} = 0 180 Pu **Power Consumption** - 3 μΑ ΜΑΧ - 2 V_{LC} == 0V **Logic Control Input Current** LC Sample Mode μΑ ΜΑΧ - 15 15 V_{S/H} = 0.6V Logic Input 15/H Hold Mode 0 na Max 0 V_{5/H} = 5V 2.0 V MAX 2.0 Differential Logic V_{TH} $V_{LC} \neq 0$ V MIN 0.8 Threshold

NOTES:

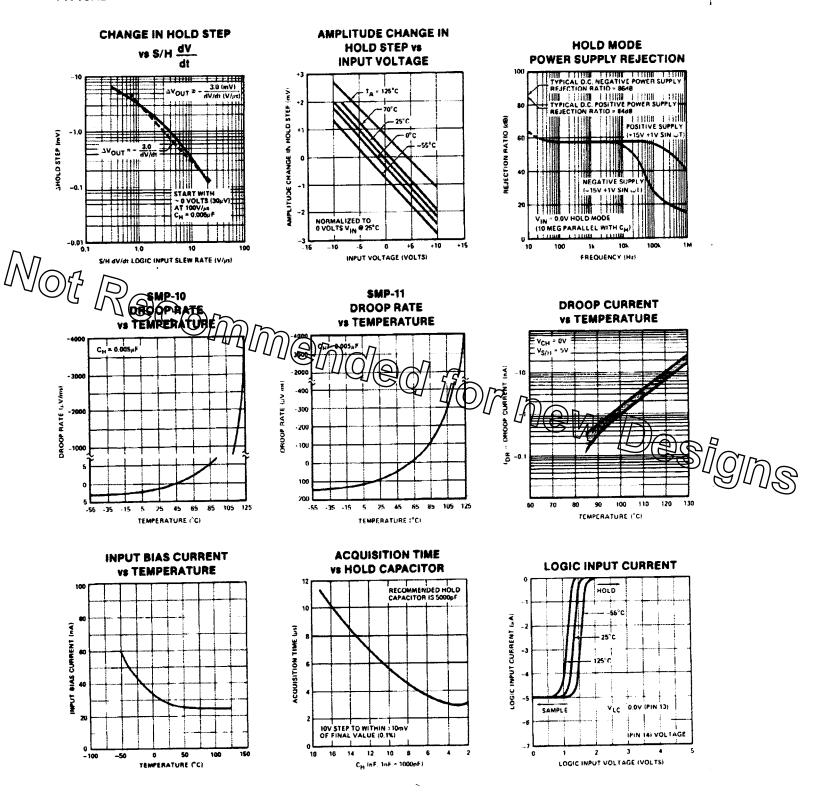
Electrical tests are performed at wafer probe to the limits shown. Due to variations in assembly methods and normal yield loss, yield after packaging is not guaranteed for standard product dice. Consult factory to negotiate specifications based on dice lot qualification through sample lot assembly and testing.

TYPICAL ELECTRICAL CHARACTERISTICS at $V_S=\pm\,15V$, $C_H=0.005\mu F$, V_{LC} connected to ground, $T_A=25^{\circ}C$, unless otherwise noted.

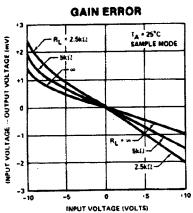
PARAMETER	SYMBOL	CONDITIONS	SMP-10N SMP-11N TYPICAL	SMP-10G SMP-11G TYPICAL	UNITS μs
Acquisition Time	t _{ac}	10V step to 0.1% of final value	3.5	3.5	
Aperture Time	tan		50	50	ns
Charge Transfer	Qt	V _{IN} = 0, V _{S/H} = 3.5V	5	5	рС
Slew Rate	SR	V _{IN} = ± 10V, R _L = 2.5k()	10	10	V/μS

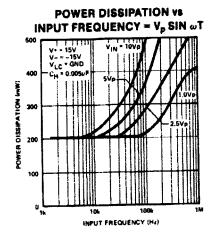
Measured 500µs after hold command.

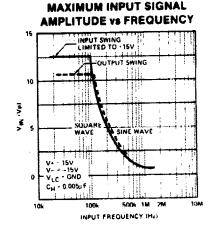
TYPICAL PERFORMANCE CHARACTERISTICS



TYPICAL PERFORMANCE CHARACTERISTICS

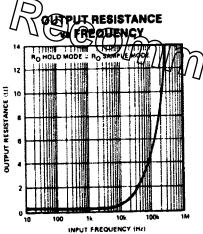


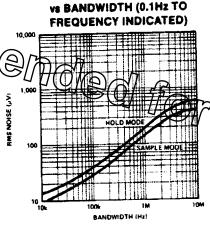




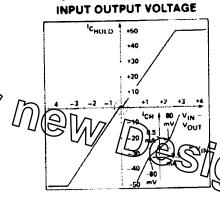
HOLD CAPACITOR

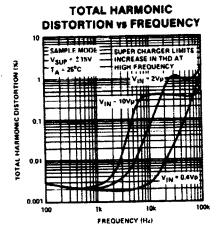
CHARGING CURRENT VS

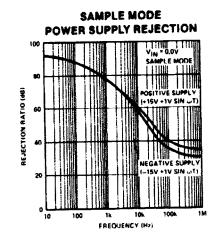


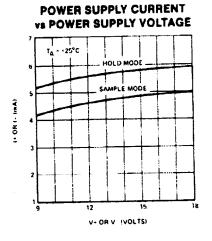


OUTPUT WIDEBAND NOISE

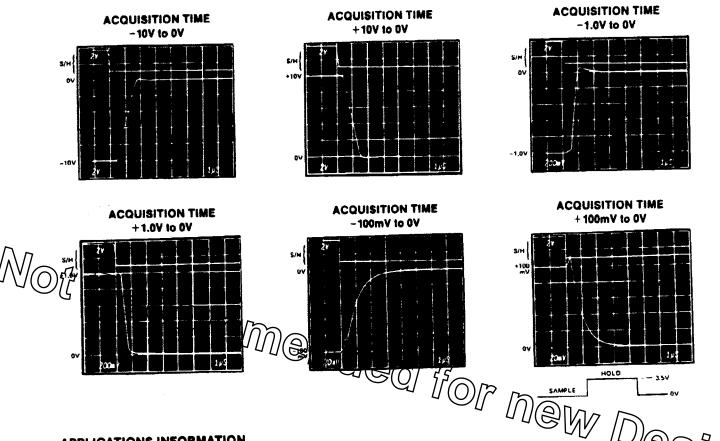








SMP-10/SMP-11 ACQUISITION TIMES



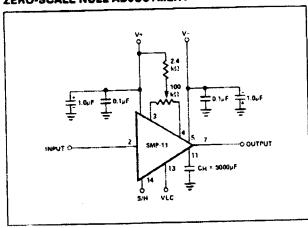
APPLICATIONS INFORMATION

During the null adjustment, the amplifier should be switched continuously between the "sample" and "hold" mode. The error should be adjusted to read zero when the unit is in the "hold" mode. In this way, both offset voltage errors and charge transfer errors are adjusted to zero.

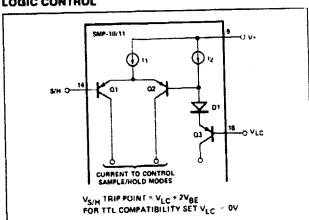
As shown in the Figure, the sample/hold mode on accomplished by steering the current (I1) through Q1 or Q2 thus providing high-speed switching and a predictable logic threshold. For TTL and DTL interface, simply ground VLC (Pin 13). For CMOS, HTL and HNIL interface, the appropriate

HOLD

ZERO-SCALE NULL ADJUSTMENT



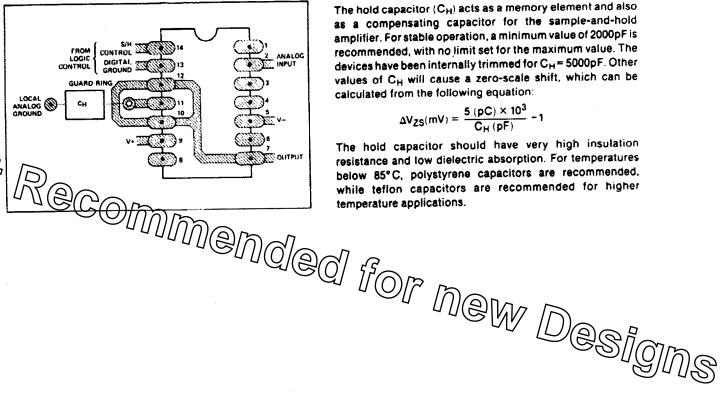
LOGIC CONTROL



threshold voltage, allowing for 2 diode drops for D1 and $V_{\mbox{\footnotesize{BE}}}$ of Q3, should be applied to VLC.

For proper operation, the V_{LC} (logic control) must always be at least 3.5V below the positive supply and 2.0V above the negative supply.

Sample-and-hold control voltage (S/H) must always be at least 2.8V above the negative supply.



GUARDING AND GROUNDING LAYOUT

The use of a ground plane is strongly recommended to minimize ground path resistances. Separate analog and digital grounds should be used, and it is advisable to keep these two ground systems isolated until they are tied back to the common system ground. Digital currents should not flow back to the system ground through the analog ground path.

HOLD CAPACITOR RECOMMENDATIONS

The hold capacitor (CH) acts as a memory element and also as a compensating capacitor for the sample-and-hold amplifier. For stable operation, a minimum value of 2000pF is recommended, with no limit set for the maximum value. The devices have been internally trimmed for CH= 5000pF. Other values of CH will cause a zero-scale shift, which can be calculated from the following equation:

$$\Delta V_{ZS}(mV) = \frac{5 (pC) \times 10^3}{C_H (pF)} - 1$$

The hold capacitor should have very high insulation resistance and low dielectric absorption. For temperatures